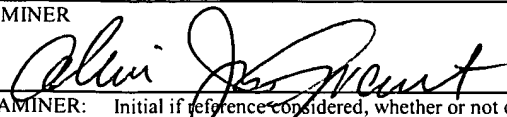
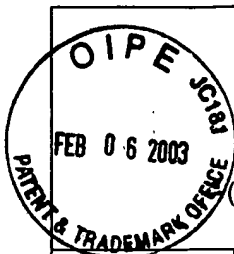
 INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449 (Modified) Use several sheets if necessary				COMPLETE IF KNOWN	
				Application Number	09/887,767
				Confirmation Number	9072
				Filing Date	June 21, 2001
				First Named Inventor	Whonchee Lee
				Group Art Unit	3723
				Examiner Name	Alvin J. Grant
Attorney Docket No.	10829851US2				
Sheet	2	of	4		

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
AS	AO	5,300,155		Sandhu et al.	04/05/1994	
AS	AP	5,575,885		Hirabayashi et al.	11/19/1996	
AS	AQ	5,618,381		Doan et al.	04/08/1997	
AS	AR	5,676,587		Landers et al.	10/14/1997	
AS	AS	5,681,423		Sandhu et al.	10/28/1997	
AS	AT	5,780,358		Zhou et al.	07/14/1998	
AS	AU	5,840,629		Carpio	11/24/1998	
AS	AV	5,846,398		Carpio	12/08/1998	
AS	AW	5,863,307		Zhou et al.	01/26/1999	
AS	AX	5,897,375		Watts et al.	04/27/1999	
AS	AY	5,934,980		Koos et al.	08/10/1999	
AS	AZ	5,954,975		Cadien et al.	09/21/1999	
AS	BA	5,954,997		Kaufman et al.	09/21/1999	
AS	BB	5,972,792		Hudson	10/26/1999	
AS	BC	6,001,730		Farkas et al.	12/14/1999	
AS	BD	6,010,964		Glass	01/04/2000	
AS	BE	6,039,633		Chopra	03/21/2000	
AS	BF	6,046,099		Cadien et al.	04/04/2000	
AS	BG	6,051,496		Jang	04/18/2000	
AS	BH	6,060,386		Givens	05/09/2000	
AS	BI	6,060,395		Skrovan et al.	05/09/2000	
AS	BJ	6,063,306		Kaufman et al.	05/16/2000	
AS	BK	6,066,030		Uzoh	05/23/2000	
AS	BL	6,066,559		Gonzalez et al.	05/23/2000	
AS	BM	6,068,787		Grumbine et al.	05/30/2000	

RECEIVED
 FEB 20 2003
 TECHNOLOGY CENTER R3700

EXAMINER 	DATE CONSIDERED 3/6/03
*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).	


**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

 Form PTO-1449 (Modified)
(Use several sheets if necessary)

COMPLETE IF KNOWN

Application Number	09/887,767
Confirmation Number	9072
Filing Date	June 21, 2001
First Named Inventor	Whonchee Lee
Group Art Unit	3723
Examiner Name	Alvin J. Grant
Attorney Docket No.	108298515US2

Sheet 1 of 4

U.S. PATENT DOCUMENTS

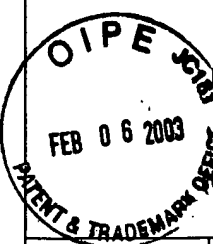
Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
AS	AA	U.S. Application No. 09/651,779 (Atty. Docket No. 10829.8515US)		Moore	Filed 08/30/2000	
AS	AB	U.S. Application No. 09/651,808 (Atty. Docket No. 4373US)		Chopra et al.	Filed 08/30/2000	
AS	AC	U.S. Application No. 09/653,392 (Atty. Docket No. MTI-31044)		Chopra et al.	Filed 08/31/2000	
AS	AD	U.S. Application No. 09/888,002 (Atty. Docket No. 10829.8515US3)		Lee et al.	Filed 06/21/2001	RECEIVED FEB 20 2003 TECHNOLOGY CENTER R3700
AS	AE	U.S. Application No. 09/888,084 (Atty. Docket No. 10829.8515US3)		Lee et al.	Filed 06/21/2001	
AS	AF	U.S. Application No. 10/090,869 (Atty. Docket No. 10829.8544US)		Moore et al.	Filed 03/04/2002	
AS	AG	U.S. Application No. 10/230,463 (Atty. Docket No. 10829.8672US)		Lee et al.	Filed 08/29/2002	
AS	AH	U.S. Application No. 10/230,602 (Atty. Docket No. 10829.8674US)		Chopra	Filed 08/29/2002	
AS	AI	U.S. Application No. 10/230,628 (Atty. Docket No. 10829.8673US)		Lee et al.	Filed 08/29/2002	
AS	AJ	U.S. Application No. 10/230,970 (Atty. Docket No. 10829.8515US6)		Lee et al.	Filed 08/29/2002	
AS	AK	U.S. Application No. 10/230,972 (Atty. Docket No. 10829.8515US7)		Lee et al.	Filed 08/29/2002	
AS	AL	U.S. Application No. 10/230,973 (Atty. Docket No. 10829.8515US8)		Lee et al.	Filed 08/29/2002	
AS	AM	4,839,005		Katsumoto et al.	06/13/1989	
AS	AN	5,244,534		Yu et al.	09/14/1993	

EXAMINER

DATE CONSIDERED

3/6/03

*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449 (Modified) (Use several sheets if necessary)				COMPLETE IF KNOWN	
				Application Number	09/887,767
				Confirmation Number	9072
				Filing Date	June 21, 2001
				First Named Inventor	Whonchee Lee
				Group Art Unit	3723
Examiner Name	Alvin J. Grant				
Attorney Docket No.	10829851US2				
Sheet	3	of	4		

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
<i>AS</i>	BN	6,083,840		Mravic et al.	07/04/2000	
<i>AS</i>	BO	6,100,197		Hasegawa	08/08/2000	
<i>AS</i>	BP	6,103,628		Talieh	08/15/2000	
<i>AS</i>	BQ	6,196,899	B1	Chopra et al.	03/06/2001	
<i>AS</i>	BR	6,206,756	B1	Chopra et al.	03/27/2001	
<i>AS</i>	BS	6,250,994	B1	Chopra et al.	06/26/2001	
<i>AS</i>	BT	6,273,786	B1	Chopra et al.	08/14/2001	
<i>AS</i>	BU	6,276,996	B1	Chopra	08/21/2001	
<i>AS</i>	BV	6,299,741	B1	Sun et al.	10/09/2001	
<i>AS</i>	BW	6,313,038	B1	Chopra et al.	11/06/2001	
<i>AS</i>	BX	6,328,632	B1	Chopra	12/11/2001	
<i>AS</i>	BY	6,368,190	B1	Easter et al.	04/09/2002	


RECEIVED
FEB 20 2003
TECHNOLOGY CENTER R3700

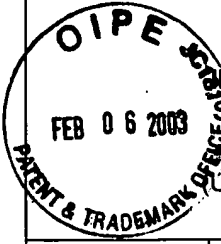
FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Foreign Patent or Application			Name of Patentee or Applicant of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
		Office	NUMBER	Kind Code (if known)				
<i>AS</i>	BZ	WO	00/26443		Talieh	05/11/2000		
<i>AS</i>	CA	WO	00/28586		Chopra	05/18/2000		
<i>AS</i>	CB	WO	00/32356		Talieh	06/08/2000		
<i>AS</i>	CC	WO	00/59008		Talieh	10/05/2000		
<i>AS</i>	CD	WO	00/59682		Talieh	10/12/2000		

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS

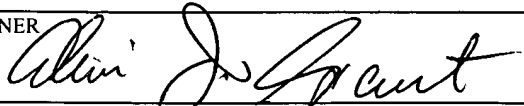
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T
<i>AS</i>	CE	FRANKENTHAL, R.P. and EATON, D.H., "Electroetching of Platinum in the Titanium-Platinum-Gold Metallization on Silicon Integrated Circuits," <i>Journal of The Electrochemical Society</i> , Vol. 123, No. 5, pp. 703-706, May 1976.	

EXAMINER 	DATE CONSIDERED 3/6/03
*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).	

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449 (Modified) Use several sheets if necessary				COMPLETE IF KNOWN	
				Application Number	09/887,767
				Confirmation Number	9072
				Filing Date	June 21, 2001
				First Named Inventor	Whonchee Lee
				Group Art Unit	3723
Examiner Name	Alvin J. Grant				
Attorney Docket No.	108298515US2				
Sheet	4	of	4		

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T	
AS	CF	BERNHARDT, A.F., CONTOLINI, R.J., MAYER, S.T., "Electrochemical Planarization for Multi-Level Metallization of Microcircuitry," <i>CircuiTree Journal</i> , Vol. 8, No. 10, pp. 38, 40, 42, 44, 46, and 48, Oct. 1995.		
AS	CG	HUANG, C.S. et al., "A Novel UV Baking Process to Improve DUV Photoresist Hardness," pp. 135-138.		
AS	CH	McGraw-Hill, <i>Concise Encyclopedia of Science & Technology</i> , Sybil P. Parker, Editor in Chief, Fourth Edition, p. 367, McGraw-Hill, New York, New York, 1998.		
AS	CI	ATMI Table of Contents, presented at the Semicon West '99 Low Dielectric Materials Technology Conference, July 12, 1999, pp. 13-25.		
AS	CJ	Micro Photonics, Inc., CSM Application Bulletin, "Low-load Micro Scratch Tester (MST) for characterisation of thin polymer films," http://www.microphotonics.com/mstABpoly.html , 7/25/2002, 3 pages.		
AS	CK	Micro Photonics, Inc., "CSM Nano Hardness Tester," http://www.microphotonics.com/nht.html , 7/29/2002, 6 pages.		
AS	CL	PhysicsWorld – Table of Contents, PhysicsWeb, "Hard Materials," http://physicsweb.org/box/world/11/1/11/world-11-1-11-1 , 7/29/2002, 1 page.		

FEB 20 2003
 TECHNOLOGY CENTER R3700

EXAMINER 	DATE CONSIDERED 3/6/03
*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).	